

FDW2502P

Dual P-Channel 2.5V Specified PowerTrench® MOSFET

General Description

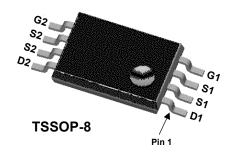
This P-Channel 2.5V specified MOSFET is a rugged gate version of Fairchild's Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V –12V).

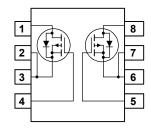
Applications

- Load switch
- Motor drive
- DC/DC conversion
- · Power management

Features

- -4.4 A, -20 V. $R_{DS(ON)}$ = 35 m Ω @ V_{GS} = -4.5 V $R_{DS(ON)}$ = 57 m Ω @ V_{GS} = -2.5 V.
- $\bullet~$ Extended V_{GSS} range (±12V) for battery applications.
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS(ON)}}$.
- Low profile TSSOP-8 package.





Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	-4.4	А
	– Pulsed		-30	
P _D	Power Dissipation for Single Operation	(Note 1a)	1.0	W
		(Note 1b)	0.6	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	125	°C/W
		(Note 1b)	208	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
2502P	FDW2502P	13"	12mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	•	·		I.	I.
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-20			V
$\Delta BV_{DSS} \over \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-14		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$			– 1	μΑ
I_{GSS}	Gate-Body Leakage	$V_{GS} = \pm 12 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.4	-0.9	-1.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = –250 μA, Referenced to 25°C		3.2		mV/°C
$R_{DS(on)}$	Static Drain–Source On–Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -4.4 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -4.4 \text{ ,} T_J = 125 ^{\circ}\text{C}$ $V_{GS} = -2.5 \text{ V}, I_D = -3.3 \text{ A}$		27 35 38	35 56 57	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, \qquad V_{DS} = -5 \text{ V}$	-30			Α
g _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, \qquad I_{D} = -4.4 \text{ A}$		18		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	V 40.V V 0.V		1465		pF
C _{oss}	Output Capacitance	$V_{DS} = -10 \text{ V}, \qquad V_{GS} = 0 \text{ V},$ $V_{GS} = 0 \text{ V},$		310		pF
C _{rss}	Reverse Transfer Capacitance	1 - 1.0 WHZ		155		pF
R_{G}	Gate Resistance	$V_{GS} = 15 \text{ mV}, f = 1.0 \text{ MHz}$		7.7		Ω
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn–On Delay Time			14	25	ns
t _r	Turn-On Rise Time	$V_{DD} = -10 \text{ V}, \qquad I_{D} = -1 \text{ A},$		8	16	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		51	82	ns
t _f	Turn-Off Fall Time			29	47	ns
Q_g	Total Gate Charge	$V_{DS} = -5 \text{ V}, \qquad I_{D} = -4.4 \text{ A}, \\ V_{GS} = -5 \text{ V}$		15	21	nC
Q_{gs}	Gate-Source Charge			2.9		nC
Q_{gd}	Gate-Drain Charge			3.5		nC
Drain-So	ource Diode Characteristics	and Maximum Ratings				
t _{rr}	Diode Reverse Recovery Time	I _F = -4.4 A,		21		ns
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$		8.1		nC
Is	Maximum Continuous Drain-Source	Diode Forward Current			-0.83	Α
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -0.83 \text{ A (Note 2)}$		-0.7	-1.2	V

Notes

^{1.} R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.

a) $\rm\,R_{\rm \theta JA}$ is 125°C/W (steady state) when mounted on a 1 inch² copper pad on FR-4.

b) $R_{\theta,JA}$ is 208°C/W (steady state) when mounted on a minimum copper pad on FR-4.

^{2.} Pulse Test: Pulse Width < 300μ s, Duty Cycle < 2.0%

Typical Characteristics

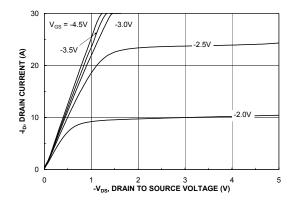


Figure 1. On-Region Characteristics.

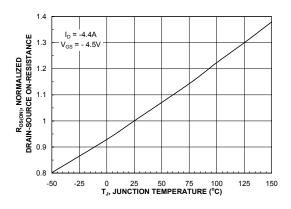


Figure 3. On-Resistance Variation with Temperature.

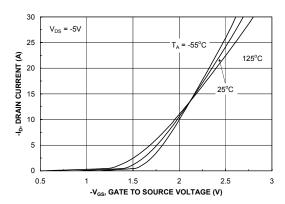


Figure 5. Transfer Characteristics.

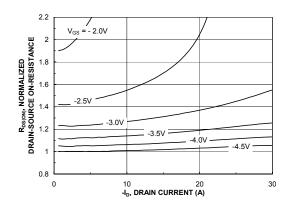


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

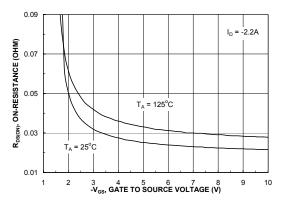


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

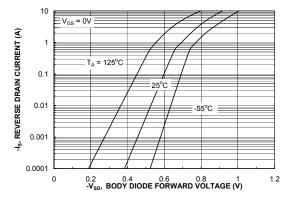
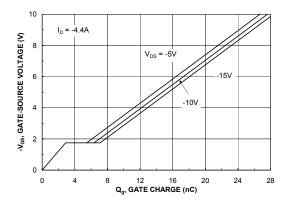


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



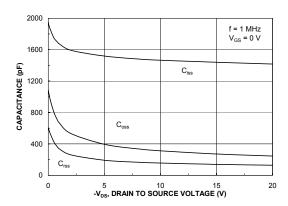
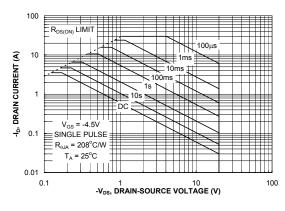


Figure 7. Gate Charge Characteristics.





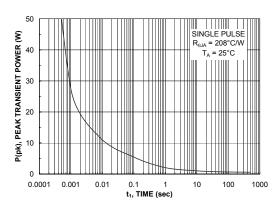


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

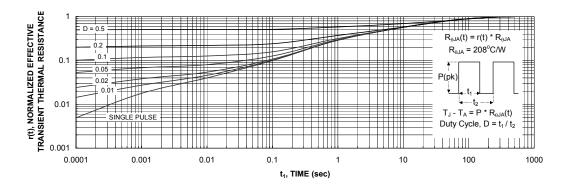


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1. Transient thermal response will change depending on the circuit board design.

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CROSSVOLT™	FRFET™	MicroPak™	QS™	SyncFET™
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